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Multiwire Laboratories, Ltd. (MWL) Hires Dr. Owen Vajk as Product and Market Development Officer

Ithaca, NY -- (August 28, 2013) -- Multiwire Laboratories, the leading supplier of equipment for real-time x-ray orientation of single crystals by the Laue back-reflection method, announces that Owen Vajk has joined MWL to increase its ability to produce, market and train industrial and academic users in the best practices of characterizing and rapidly x-ray orienting their single crystals with the industry-leading tools developed at MWL over the last 32 years, equipment that was, in part, a spin-off of NSF sponsored research at Cornell University by Donald Bilderback, one of the original MWL founders. Owen Vajk's experience with single crystal technology and wealth of material science knowledge will be very valuable in talking with customers, advising them of best practices, and training staff and students in the optimal use of the specialized x-ray equipment.

Owen Vajk joins MWL from the physics faculty of the University of Missouri where he was growing crystals of multiferroics. His Ph.D. research at Stanford University focused on the magnetic properties of high-Tc superconductors and related cuprate materials. The MWL110 real-time x-ray detector has been a key part of his research, and was used to orient crystals for inelastic neutron scattering studies at NIST (National Institute Standards and Technology, Gaithersburg, MD). According to Don Bilderback, Owen Vajk "brings a wealth of knowledge of material science and physics, of diffraction methods (both neutron and x-ray) and appropriate laboratory techniques to MWL At U. Missouri, Owen Vajk was highly valued for his teaching ability at both the undergraduate and graduate levels. We are pleased to have someone of such high caliber join our MWL production/development team."

Dr. Vajk holds a PhD degree in Physics from Stanford University (2003) and subsequently held a National Research Council Postdoctoral Research Fellowship and was a Postdoctoral Research Associate at NIST in their Center for Neutron Research. In 2004 he won the Neutron Scattering Society of America Prize for Outstanding Student Research. Also in 2004, he received the Outstanding Dissertation in Magnetism award, American Physical Society, Topical Group on Magnetism and its Applications (GMAG).

Dr. Vajk is the author of “Quantum Percolation in a Two-Dimensional Heisenberg Antiferromagnet: Crystal Growth, Magnetometry, Neutron Scattering, and Monte Carlo Simulations” (VDM Publishing, 2010), which examines the effects of disorder in a system with strong quantum fluctuations and how those two aspects relate. This book is based on his Ph.D. research at Stanford University, including work with the MWL110 real-time x-ray detector.

ABOUT MULTIWIRE LABORATORIES, LTD.
Multiwire Laboratories Ltd. develops and manufactures products for rapid x-ray orientation of single crystals by the Laue back-reflection method. Industrial and academic laboratories utilize the real-time detector, motorized orientation stages, and computer analysis of back-reflection images to characterize or determine the orientation of the lattice planes in a variety of crystal materials such as silicon, gallium arsenide, sapphire, geological minerals, high-temperature superconductors, turbine blades, etc. For more information on MWL, visit www.multiwire.com or contact salesinfo@multiwire.com.

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